

Search Notes

Application/Control No.

10/650,601

Examiner

José R. Díaz

Applicant(s)/Patent under
Reexamination

LIN, SHI-CHI

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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